

# INTERNATIONAL STANDARD

**IEC**  
**60444-8**

First edition  
2003-07

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## Measurement of quartz crystal unit parameters –

### Part 8: Test fixture for surface mounted quartz crystal units

*Mesure des paramètres des résonateurs à quartz –*

*Partie 8:  
Dispositif d'essai pour les résonateurs à quartz  
montés en surface*

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## INTERNATIONAL ELECTROTECHNICAL COMMISSION

**MEASUREMENT OF QUARTZ CRYSTAL UNIT PARAMETERS –****Part 8: Test fixture for surface mounted quartz crystal units**

## FOREWORD

- 1) The International Electrotechnical Commission (IEC) is a worldwide organization for standardization comprising all national electrotechnical committees (IEC National Committees). The object of IEC is to promote international co-operation on all questions concerning standardization in the electrical and electronic fields. To this end and in addition to other activities, IEC publishes International Standards, Technical Specifications, Technical Reports, and Guides (hereafter referred to as "IEC Publication(s)"). Their preparation is entrusted to technical committees; any IEC National Committee interested in the subject dealt with may participate in this preparatory work. International, governmental and non-governmental organizations liaising with the IEC also participate in this preparation. IEC collaborates closely with the International Organization for Standardization (ISO) in accordance with conditions determined by agreement between the two organizations.
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International Standard IEC 60444-8 has been prepared by IEC technical committee 49: Piezoelectric and dielectric devices for frequency control and selection.

This International Standard cancels and replaces IEC/PAS 62277 published in 2001, of which it constitutes a technical revision.

The text of this standard is based on the following documents:

FDIS	Report on voting
49/599/FDIS	49/611/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

This standard forms Part 8 of a series of publications dealing with measurements of quartz crystal unit parameters.

IEC 60444 consists of the following parts under the general title *Measurement of quartz crystal unit parameters*:

- Part 1: Basic method for the measurement of resonance frequency and resonance resistance of quartz crystal units by zero phase technique in a  $\pi$ -network
- Part 2: Phase offset method for measurement of motional capacitance of quartz crystal units
- Part 4: Method for the measurement of the load resonance frequency  $f_L$ , load resonance resistance,  $R_L$  and the calculation of other derived values of quartz crystal units, up to 30 MHz
- Part 5: Methods for the determination of equivalent electrical parameters using automatic network analyzer techniques and error correction
- Part 6: Measurement of drive level dependence (DLD)
- Part 7: Measurement of activity and frequency dips of quartz crystal units<sup>1</sup>

The committee has decided that the contents of this publication will remain unchanged until 2007. At this date, the publication will be

- reconfirmed;
- withdrawn;
- replaced by a revised edition, or
- amended.

A bilingual version of this standard may be issued at a later date.

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<sup>1</sup> Under consideration.